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				Application Number	Not Yet Assigned
				Confirmation Number	Not Yet Assigned
				Filing Date	January 29, 2004
				First Named Inventor	Markus MENGEL
				Art Unit	Not Yet Assigned
Examiner Name	Not Yet Assigned				
Sheet	1	of	1	Attorney Docket Number	Q79656

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US 5 965 874		10/12/1999	THE FURUKAWA ELECTRIC CO., LTD
		US 5 396 329		3/7/1995	BRITISH AEROSPACE PLC
		US 5 298 972		3/29/1994	HEWLETT-PACKARD COMPANY
		US 5 227 623		7/13/1993	HEWLETT-PACKARD COMPANY
		US 5 166 752		11/24/1992	RUDOLPH RESEARCH CORPORATION
		US 6 204 924		3/20/2001	EXFO ELECTRO-OPTICAL ENGINEERING INC.
		US 6 312 373	B1	11/6/2001	NIKON CORPORATION
		US 6 344 898	B1	2/5/2002	NIKON CORPORATION
		US 2002/0024673	A1	2/28/2002	CHIDANE OUCHI

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
		DE	101 09 929	A1	11/22/2001	CARL ZEISS	
		EP	0 439 127	A2	7/31/1991	HEWLETT-PACKARD COMPANY	
		EP	0 396 409	A2	11/7/1990	THERMA-WAVE INC.	
		JP	11-142291	A	5/28/1999	NIKON CORPORATION	Abstract
		WO	02/42728	A1	5/30/2002	NIKON CORPORATION	Abstract
		WO	03/028073	A1	4/3/2003	NIKON CORPORATION	Claims

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
		"OPTICAL SHOP TESTING", EDITED BY: DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
		MICHAEL I. SHRIBAK ET AL, "RETURN-PATH POLARIMETER FOR TWO DIMENSIONAL BIREFRINGENCE DISTRIBUTION MEASUREMENT", JULY 1999, SPIE, PAGES 144-145 AND 148-149, VOLUME 3654, DENVER COLORADO	
		S. BEREZHNA, ET AL, "ACCURACY OF WHOLE-FIELD MAPPING BY JONES MATRIX FOURIER PHOTOPOLARIMETER", 2000, PROCEEDINGS OF SPIE, PAGES 81-89, VOLUME 4148	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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